Sheet 1 of 5 Form PTO-1449 ATTY, DOCKET NO. SERIAL NO. M122-1898 10/050,348 U.S. DEPARTMENT OF COMMERCE **APPLICANT** ENTENT AND TRADEMARK OFFICE Gurtej S. Sandhu LIST OF ART CITED BY APPLICANT **GROUP** FILING DATE IAN 0 4 2006 (Use several sheets if necessary) January 15, 2002 2813 TO THAT U.S. PATENT DOCUMENTS Name Class Subclass Filing Date Examiner Document Initial Number If Appropriate AA 12-1971 McDonald et al. 3,627,598 ΑB 4,254,161 03-1981 Kemlage AC 04-1981 Kubacki 4,262,631 AD 4,435,447 03-1984 lto et al. ΑE 4,882,649 11-1989 Chen et al. ΑF 01-1990 Nishioka et al. 4,891,684 AG 4,980,307 12-1990 Ito et al. AΗ 4,996,081 02-1991 Ellul et al. ΑI 5,051,794 09-1991 Mori ΑJ 08-1992 5,142,438 Reinberg et al. FOREIGN PATENT DOCUMENTS Class Subclass Date Translation Document Country Number Yes No ΑK **EPO** EP 0886308 A2 12-1998 ΑL 04-2001 237243 a Japan ANT OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) ΑN Wolf, Stanley, Silicon Processing for the VLSI Era (1995), V.3, 648-9 λO Laughery et al., Effect of H₂ Content on Reliability of ... 2/2/06 **EXAMINER** DATE CONSIDERED Soluter • EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to

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